

POLITICAL SCIENCE AND INTERNATIONAL RELATIONS

Technology Assessment in a Globalized World

<https://doi.org/10.1007/978-3-031-10617-0>

Authour : Leonhard Hennen, Julia Hahn, Miltos Ladikas, Ralf Lindner,
Walter Peissl, Rinie van Est
Publisher : Springer Cham
Year : 2023
ISBN : 978-3-031-10617-0